PH20100S

N-channel TrenchMOS standard level FET

Rev. 03 — 2 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge current

1.3 Applications

■ DC-to-DC convertors

Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	100	V
I_D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 2</u> ; see <u>Figure 1</u>	-	-	34.3	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 20 \text{ A};$ $V_{DS} = 50 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	8.9	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 8}}{\text{see } \frac{\text{Figure 9}}{\text{otherwise}}}$	-	19	23	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		$G \longrightarrow \overline{A}$
4	G	gate	9	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH20100S	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

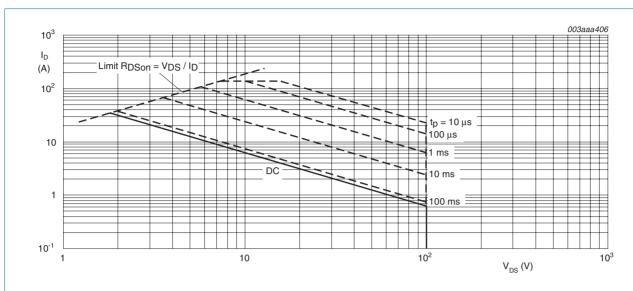
4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

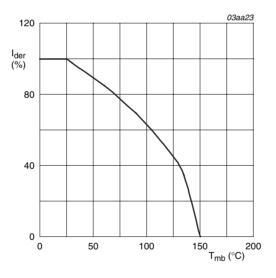
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	100	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 2</u>	-	21.6	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 2</u> ; see <u>Figure 1</u>	-	34.3	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 1	-	137	Α
P _{tot}	total power dissipation	$T_{mb} = 25 ^{\circ}C$	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	52	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	137	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 12 A; $V_{sup} \le$ 100 V; unclamped; t_p = 0.3 ms	-	250	mJ

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 $T_{mb} = 25$ °C; I_{DM} is single pulse; $V_{GS} = 10V$

Fig 1. Safe operating area; continuous and peak drain currents as a function of drain-source voltage



 $I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$

Fig 2. Normalized continuous drain current as a function of mounting base temperature

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Thermal characteristics

Thermal characteristics Table 5.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 3	-	-	2	K/W

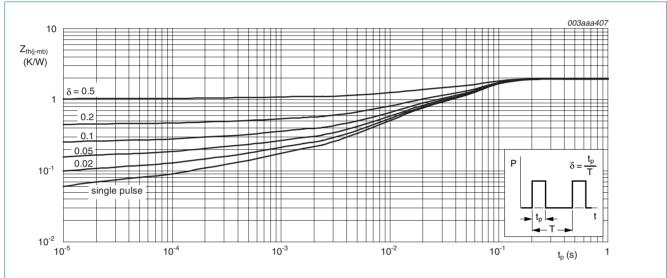


Fig 3. Transient thermal impedance from junction to mounting base as a function of pulse duration

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6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 1 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	100	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 7	2	3	4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 7</u>	1.2	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.06	1	μΑ
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	500	μΑ
I_{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon} drain-source on- resistance	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A}; T_j = 150 ^{\circ}\text{C};$ see <u>Figure 8</u> ; see <u>Figure 9</u>	-	43	53	mΩ
		V_{GS} = 10 V; I_D = 10 A; T_j = 25 °C; see <u>Figure 8</u> ; see <u>Figure 9</u>	-	19	23	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 20 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$	-	39	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	6.9	-	nC
Q_{GD}	gate-drain charge		-	8.9	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2264	-	рF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	290	-	pF
C _{rss}	reverse transfer capacitance		-	111	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 50 \text{ V}; R_L = 5 \Omega; V_{GS} = 10 \text{ V};$	-	23	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega; I_D = 10 A; T_j = 25 °C$	-	15	-	ns
t _{d(off)}	turn-off delay time		-	47	-	ns
t _f	fall time		-	9.3	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 10 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 10</u>	-	0.8	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$; $V_{DS} = 25 \text{ V}$; $T_i = 25 \text{ °C}$	-	110	-	ns

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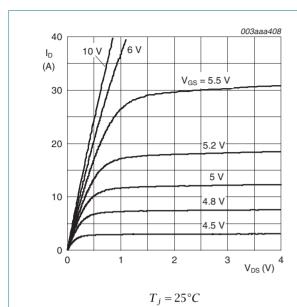
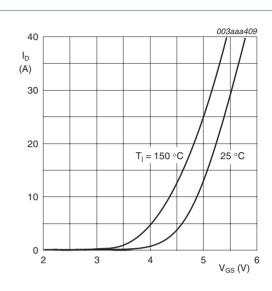
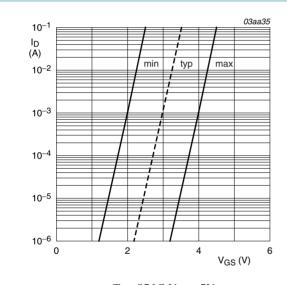


Fig 4. Output characteristics: drain current as a function of drain-source voltage; typical values



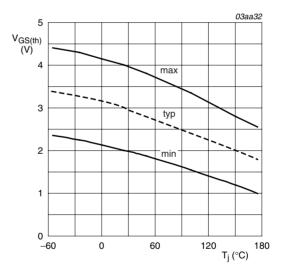
 $T_j = 25$ °C and 150°C; $V_{DS} > I_D \times R_{DSon}$

Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$

Fig 6. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 7. Gate-source threshold voltage as a function of junction temperature

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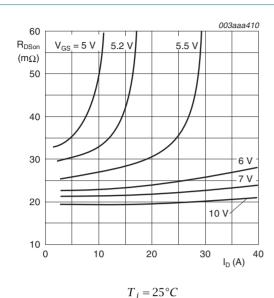


Fig 8. Drain-source on-state resistance as a function of drain current; typical values

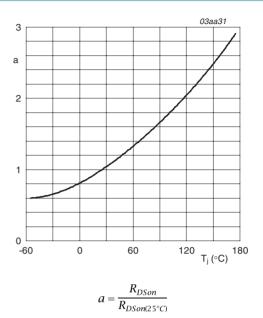
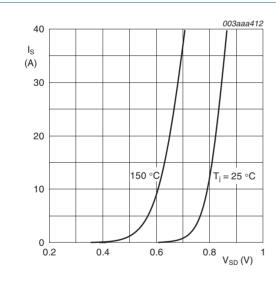
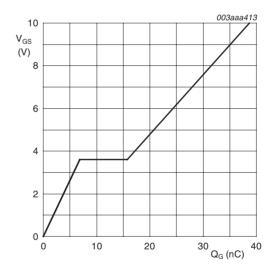


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_j = 25$ °C and 150°C; $V_{GS} = 0V$

Fig 10. Source current as a function of source-drain voltage; typical values



$$I_D = 20A; V_{DS} = 50V$$

Fig 11. Gate-source voltage as a function of gate charge; typical values

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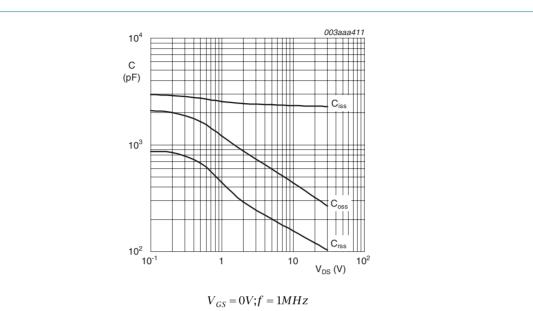


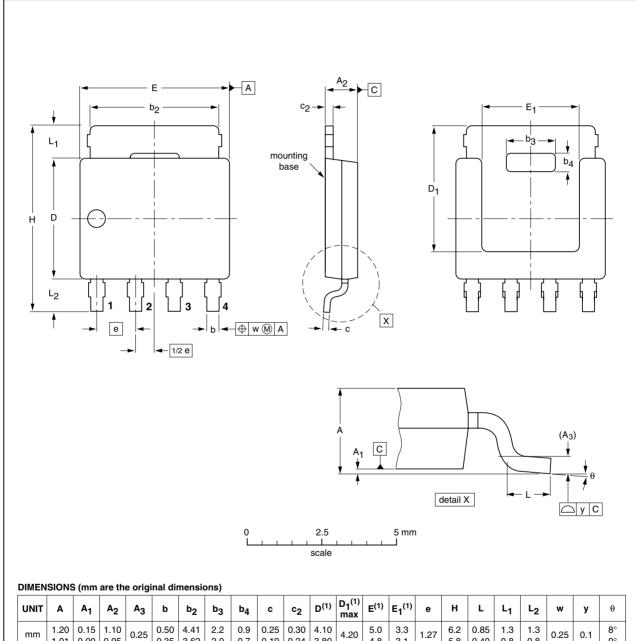
Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNI	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	0.30 0.24	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT669		MO-235			04-10-13 06-03-16	

Fig 13. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH20100S_3	20090202	Product data sheet	-	PH20100S_2
Modifications:	guidelines o	of this data sheet has been of NXP Semiconductors. have been adapted to the		·
	Legal lexis	nave been adapted to the	new company name whe	те арргорнате.
PH20100S_2 (9397 750 13698)	20040817	Product data sheet	-	PH20100S_1
PH20100S_1 (9397 750 12815)	20040305	Preliminary data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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